

# Yoshitaka Naitoh

## List of Publications by Year in descending order

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55  
papers

1,227  
citations

430874

18  
h-index

377865

34  
g-index

56  
all docs

56  
docs citations

56  
times ranked

1375  
citing authors

#	ARTICLE	IF	CITATIONS
1	Properties of large organic molecules on metal surfaces. <i>Progress in Surface Science</i> , 2003, 71, 95-146.	8.3	419
2	One-Dimensional Assembly and Selective Orientation of Lander Molecules on an O <sub>2</sub> -Cu Template. <i>Angewandte Chemie - International Edition</i> , 2004, 43, 2092-2095.	13.8	99
3	Origin of p(2 $\times$ 1) Phase on Si(001) by Noncontact Atomic Force Microscopy at 5 $\text{\AA}$ . <i>Physical Review Letters</i> , 2006, 96, 106104.	7.8	52
4	High potential sensitivity in heterodyne amplitude-modulation Kelvin probe force microscopy. <i>Applied Physics Letters</i> , 2012, 100, .	3.3	51
5	The stray capacitance effect in Kelvin probe force microscopy using FM, AM and heterodyne AM modes. <i>Nanotechnology</i> , 2013, 24, 225701.	2.6	45
6	Nanostructuring Cu Surfaces Using Custom-Designed Molecular Molds. <i>Nano Letters</i> , 2004, 4, 75-78.	9.1	42
7	Optical force mapping at the single-nanometre scale. <i>Nature Communications</i> , 2021, 12, 3865.	12.8	30
8	Elimination of instabilities in phase shift curves in phase-modulation atomic force microscopy in constant-amplitude mode. <i>Applied Physics Letters</i> , 2007, 90, 194104.	3.3	28
9	Multifrequency high-speed phase-modulation atomic force microscopy in liquids. <i>Ultramicroscopy</i> , 2010, 110, 582-585.	1.9	25
10	Simultaneous observation of surface topography and elasticity at atomic scale by multifrequency frequency modulation atomic force microscopy. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , 2010, 28, 1210-1214.	1.2	25
11	The influence of a Si cantilever tip with/without tungsten coating on noncontact atomic force microscopy imaging of a Ge(001) surface. <i>Nanotechnology</i> , 2009, 20, 264011.	2.6	24
12	High-Sensitivity Force Detection by Phase-Modulation Atomic Force Microscopy. <i>Japanese Journal of Applied Physics</i> , 2006, 45, L793-L795.	1.5	21
13	Fabrication of sharp tungsten-coated tip for atomic force microscopy by ion-beam sputter deposition. <i>Review of Scientific Instruments</i> , 2011, 82, 113707.	1.3	21
14	Surface potential imaging with atomic resolution by frequency-modulation Kelvin probe force microscopy without bias voltage feedback. <i>Nanotechnology</i> , 2015, 26, 195701.	2.6	21
15	Development of low temperature atomic force microscopy with an optical beam deflection system capable of simultaneously detecting the lateral and vertical forces. <i>Review of Scientific Instruments</i> , 2016, 87, 093113.	1.3	20
16	Investigation of tunneling current and local contact potential difference on the TiO <sub>2</sub> (110) surface by AFM/KPFM at 78 K. <i>Nanotechnology</i> , 2017, 28, 105704.	2.6	20
17	Subatomic-scale force vector mapping above a Ge(001) dimer using bimodal atomic force microscopy. <i>Nature Physics</i> , 2017, 13, 663-667.	16.7	19
18	Study of oxidized Cu(110) surface using noncontact atomic force microscopy. <i>Surface Science</i> , 2008, 602, 2175-2182.	1.9	18

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19	Development of atomic force microscope with wide-band magnetic excitation for study of soft matter dynamics. <i>Review of Scientific Instruments</i> , 2009, 80, 023705.	1.3	17
20	Magnetic force microscopy using tip magnetization modulated by ferromagnetic resonance. <i>Nanotechnology</i> , 2015, 26, 125701.	2.6	17
21	Effect of Surface Stress around the S <sub>A</sub> Step of Si(001) on the Dimer Structure Determined by Noncontact Atomic Force Microscopy at 5 K. <i>Journal of the Physical Society of Japan</i> , 2010, 79, 013601.	1.6	14
22	High-Speed Phase-Modulation Atomic Force Microscopy in Constant-Amplitude Mode Capable of Simultaneous Measurement of Topography and Energy Dissipation. <i>Japanese Journal of Applied Physics</i> , 2008, 47, 6121.	1.5	13
23	Stable contrast mode on TiO <sub>2</sub> (110) surface with metal-coated tips using AFM. <i>Ultramicroscopy</i> , 2018, 191, 51-55.	1.9	13
24	Scanning Tunneling Microscopy and Spectroscopy Studies of Individual Lander Molecules Anchored on a Copper Oxide Nanotemplate. <i>Journal of Physical Chemistry C</i> , 2008, 112, 16118-16122.	3.1	12
25	Phase modulation atomic force microscopy in constant excitation mode capable of simultaneous imaging of topography and energy dissipation. <i>Applied Physics Letters</i> , 2008, 92, 121903.	3.3	11
26	Complex design of dissipation signals in non-contact atomic force microscopy. <i>Physical Chemistry Chemical Physics</i> , 2012, 14, 16250.	2.8	11
27	Wideband and hysteresis-free regulation of piezoelectric actuator based on induced current for high-speed scanning probe microscopy. <i>Review of Scientific Instruments</i> , 2006, 77, 103701.	1.3	10
28	Step response measurement of AFM cantilever for analysis of frequency-resolved viscoelasticity. <i>Ultramicroscopy</i> , 2010, 110, 612-617.	1.9	10
29	High force sensitivity in Q-controlled phase-modulation atomic force microscopy. <i>Applied Physics Letters</i> , 2010, 97, .	3.3	8
30	Atomic force microscopy identification of Al-sites on ultrathin aluminum oxide film on NiAl(110). <i>Nanotechnology</i> , 2015, 26, 505704.	2.6	8
31	Simultaneous observation of scanning tunneling microscopy and reflection electron microscopy image of the Si(111)7 $\times$ 7 surface. <i>Surface Science</i> , 1999, 433-435, 627-631.	1.9	7
32	Dissipative force modulation Kelvin probe force microscopy applying doubled frequency ac bias voltage. <i>Applied Physics Letters</i> , 2007, 90, 033118.	3.3	7
33	Formation process of very thin Ag structures on Ge(111) surface below RT. <i>Surface Science</i> , 2002, 513, 1-8.	1.9	6
34	Theoretical investigation on force sensitivity in Q-controlled phase-modulation atomic force microscopy in constant-amplitude mode. <i>Journal of Applied Physics</i> , 2008, 103, 054305.	2.5	6
35	Atomic-Resolution Imaging of the Optical Near Field Based on the Surface Photovoltage of a Silicon Probe Tip. <i>Physical Review Applied</i> , 2015, 3, .	3.8	6
36	Direct Visualization of Oxygen Reaction with Paired Hydroxyl on TiO <sub>2</sub> (110) Surface at 78 K by Atomic Force Microscopy. <i>Journal of Physical Chemistry C</i> , 2018, 122, 17395-17399.	3.1	6

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37	Local spectroscopic imaging of a single quantum dot in photoinduced force microscopy. Applied Physics Letters, 2022, 120, .	3.3	6
38	Study of high- and low-KPFM on a pn-patterned Si surface. Microscopy (Oxford, England), 2022, 71, 98-103.	1.5	5
39	Nanoscale optical imaging with photoinduced force microscopy in heterodyne amplitude modulation and heterodyne frequency modulation modes. Journal of Photochemistry and Photobiology C: Photochemistry Reviews, 2022, 52, 100532.	11.6	5
40	Electronic structures of Ag/Ge(001) surfaces. Surface Science, 2005, 591, 108-116.	1.9	4
41	Switching surface polarization of atomic force microscopy probe utilizing photoisomerization of photochromic molecules. Journal of Applied Physics, 2011, 109, 064308.	2.5	4
42	Quantification of Atomic-Scale Elasticity on Ge(001)-c(4x8) Surface by Noncontact Atomic Force Microscopy at 78 K. Journal of Applied Physics, 2011, 109, 064308.	7.8	4
43	Tungsten-Coated Tip. Physical Review Letters, 2012, 109, 215501. SURFACE TRANSMISSION ELECTRON MICROSCOPY ON STRUCTURES WITH TRUNCATION. Surface Review and Letters, 1997, 04, 687-694.	1.1	2
44	Force Microscopy Imaging of Rest Atom on Si(111)7x7 Surface under Strong Tip-Surface Interaction. Journal of the Physical Society of Japan, 2007, 76, 033601.	1.6	2
45	Atomic-Scale Imaging of B/Si(111)1x1 Surface by Noncontact Atomic Force Microscopy. Japanese Journal of Applied Physics, 2008, 47, 8218.	1.5	2
46	Growth models of coexisting p(2x1) and c(6x2) phases on an oxygen-terminated Cu(110) surface studied by noncontact atomic force microscopy at 78 K. Nanotechnology, 2016, 27, 205702.	2.6	2
47	Force Mapping of the NaCl(100)/Cu(111) Surface by Atomic Force Microscopy at 78 K. Japanese Journal of Applied Physics, 2012, 51, 035201.	1.5	1
48	Distance dependence of atomic-resolution near-field imaging on $\gamma$ -Al <sub>2</sub> O <sub>3</sub> (0001) surface with respect to surface photovoltage of silicon probe tip. Nano Research, 2016, 9, 530-536.	10.4	1
49	Kelvin Probe Force Microscopy with. Springer Series in Surface Sciences, 2018, , 437-463.	0.3	1
50	Spin-selective Imaging by Magnetic Exchange Force Microscopy Using Ferromagnetic Resonance. Microscopy (Oxford, England), 2014, 63, i11.2-i11.	1.5	0
51	Separation of atomic-scale spin contrast on NiO(001) by magnetic resonance force microscopy. Journal of Physics Condensed Matter, 2017, 29, 404001.	1.8	0
52	Atomic-Scale Elastic Property Probed by Atomic Force Microscopy. , 2019, , 33-52.		0
53	Influence of Surface Stress on the Phase Change in a Si(001) Step Measured by LT-NC-AFM. Hyomen Kagaku, 2007, 28, 421-427.	0.0	0
54	Development of the Magnetic Exchange Force Microscopy Using Ferromagnetic Resonance to Image Surface Spin with Atomic Resolution. Hyomen Kagaku, 2016, 37, 416-421.	0.0	0

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55	Charge State and Charge Manipulation of Oxygen Molecules Adsorbed on Rutile TiO <sub>2</sub> (110) Surface by Kelvin Probe Force Microscopy. <i>Vacuum and Surface Science</i> , 2018, 61, 639-644.	0.1	0